### research papers

Acta Crystallographica Section A Foundations of Crystallography

ISSN 0108-7673

Received 5 January 2010 Accepted 2 April 2010

# Three-beam X-ray rocking curves calculated from computer-simulated pinhole topographs

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X-ray rocking curves are reported which have been obtained by fast-Fouriertransforming X-ray amplitudes in three-beam pinhole topographs. The topographs were computer-simulated based on the Takagi–Taupin equation with the condition of spherical-wave X-ray incidence. This is another strategy for calculating three-beam rocking curves, which are usually calculated based on the Ewald–Laue dynamical theory.

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#### 1. Introduction

The Pendellösung fringes observed in X-ray section topographs have been explained by Kato's spherical-wave dynamical theory (Kato, 1961a,b, 1968a,b), which was derived based on the Ewald-Laue (E-L) dynamical theory (Ewald, 1917; von Laue, 1931). The E-L theory was extended to the three-beam case (Hildebrandt, 1967; Héno & Ewald, 1968; Ewald & Héno, 1968) in the late 1960s. X-ray intensities observed in experimentally obtained three-beam pinhole topographs were compared with computer-simulated topographs for the first time by Heyroth et al. (2001). Their simulated topographs were obtained by coherently superposing the plane-wave solutions of the three-beam E-L theory. Good agreements between experimentally obtained and computer-simulated images were reported. Studies of X-ray three-beam rocking curves are recognized to be very important, since phase information on crystal structure factors can be extracted from them (Colella, 1995a,b; Weckert & Hümmer, 1997, 1998; Shen & Wang, 2003; Chang, 2004).

On the other hand, X-ray amplitudes in section topographs calculated based on the Takagi–Taupin (T–T) equation (Takagi, 1962, 1969; Taupin, 1964) under the assumption of spherical-wave incidence are identical with those given by Kato's spherical-wave dynamical theory. Authier & Simon (1968) clarified the Fourier-transform relation between solutions of the T–T equation under the assumptions of plane- and spherical-wave incident X-rays. The T–T theory was extended to the three-beam case without taking into account the polarization effect by Thorkildsen (1987) and taking it into account by Larsen & Thorkildsen (1998). One of the present authors has extended the T–T theory into *n*-beam cases with *n* up to 12 (Okitsu, 2003). Okitsu and co-authors have given a numerical method for solving the equation and have reported good agreements between experimentally obtained and

computer-simulated six-beam pinhole topographs (Okitsu et al., 2003, 2006).

The E–L theory describes X-ray wavefields in a perfect crystal in reciprocal space. However, the behavior of X-rays in a perfect crystal can also be described by the T–T equation in real space. Because of this, the T–T equation has the significant capability of being able to deal with X-ray wavefields in a distorted crystal. Pioneering work to calculate two-beam rocking curves numerically based on the T–T equation for bent crystals (Taupin, 1964) was followed by work on silicon crystals with epilayers (Fukuhara & Takano, 1977*a*,*b*), ionimplanted garnet crystals (Takeuchi *et al.*, 1983) and crystals with surface acoustic waves (Gabrielyan & Aslanian, 1988).

In the present paper it is shown that the three-beam X-ray rocking curves for a perfect crystal can also be obtained from computer-simulated pinhole topographs based on the three-beam T–T equation.

## 2. A method for calculating X-ray rocking curves from computer-simulated three-beam pinhole topographs

In this section, a method for calculating rocking curves from X-ray amplitudes in computer-simulated three-beam pinhole topographs is described. For simplicity, the discussions are limited to a symmetrical transmission geometry for a parallel-sided crystal with a thickness of *t*. The amplitudes in real space of forward-diffracted (p = o) and reflected (p = h, g) X-rays on the exit surface of the crystal are represented as

$$D_p^{(l)}(\mathbf{r}_e) \exp(-i2\pi \mathbf{K}_p \cdot \mathbf{r}_e) = \int_{\Delta \mathbf{K}_p} D_p^{(l)}(\Delta \mathbf{K}_p) \exp[-i2\pi (\mathbf{K}_p - \Delta \mathbf{K}_p) \cdot \mathbf{r}_e] d\Delta \mathbf{K}_p, \quad (1)$$

where  $p \in \{o, h, g\}, l \in \{\sigma, \pi\}$ .

 $D_p^{(l)}(\mathbf{r}_e)$  is the X-ray amplitude of the *p*th wave with polarization state of l at  $\mathbf{r}_e$ , where  $\mathbf{r}_e$  is the location vector on the exit

surface of the crystal.  $\mathbf{K}_p$  is  $\overline{L_a H_p}$ , where  $L_a$  is the Laue point and  $H_p$  is the reciprocal-lattice node.  $\Delta \mathbf{K}_p$  is  $\overline{L_a Q_p}$ , where  $Q_p$  is a point on  $S_p$ .  $S_p$  is a plane normal to  $\mathbf{K}_p$  whose distance from  $H_p$  is K, where K is the wavenumber of X-rays in vacuum. While  $Q_p$  is in fact on the surface of a sphere whose center is  $H_p$  and radius is K, the following discussions are described based on an approximation that  $Q_p$  is on  $S_p$ , since this situation is sufficiently satisfied in the vicinity of the exact threebeam condition.  $\mathcal{D}_p^{(l)}(\Delta \mathbf{K}_p)$  is the amplitude of X-rays whose wavevector is  $\mathbf{K}_p - \Delta \mathbf{K}_p$ .  $\int_{\Delta \mathbf{K}_p} d\mathbf{K}_p$  means integration over  $S_p$ . Now let us define unit vectors  $\mathbf{s}_p$ ,  $\mathbf{e}_p^{(\sigma)}$  and  $\mathbf{e}_p^{(\pi)}$  as

$$\begin{split} \mathbf{s}_p &= \mathbf{K}_p / K, \\ \mathbf{e}_p^{(\sigma)} &= \frac{\mathbf{s}_p \times [\mathbf{s}_{(p+1)'} - \mathbf{s}_p]}{|\mathbf{s}_p \times [\mathbf{s}_{(p+1)'} - \mathbf{s}_p]|}, \\ \mathbf{e}_p^{(\pi)} &= \mathbf{s}_p \times \mathbf{e}_p^{(\sigma)}. \end{split}$$

Here, (p+1)' is *h*, *g* and *o* when *p* is *o*, *h* and *g*, respectively. Substituting  $\mathbf{r}_{e} = s_{p}\mathbf{s}_{p} + e_{p}^{(\sigma)}\mathbf{e}_{p}^{(\sigma)} + e_{p}^{(\pi)}\mathbf{e}_{p}^{(\pi)}$  and  $\Delta \mathbf{K}_{p} = \eta_{p}^{(\sigma)}\mathbf{e}_{p}^{(\sigma)} + \eta_{p}^{(\pi)}\mathbf{e}_{p}^{(\pi)}$  into equation (1), the following equation can be obtained:

$$D_p^{(l)}(\mathbf{r}_{\rm e}) = \int_{-\infty}^{\infty} \int_{-\infty}^{\infty} \mathcal{D}_p^{(l)}(\Delta \mathbf{K}_p) \\ \times \exp\left[i2\pi(\eta_p^{(\sigma)}e_p^{(\sigma)} + \eta_p^{(\pi)}e_p^{(\pi)})\right] \mathrm{d}\eta_p^{(\sigma)} \,\mathrm{d}\eta_p^{(\pi)}.$$
(2)

Therefore, the X-ray amplitude  $\mathcal{D}_p^{(l)}(\Delta \mathbf{K}_p)$  in reciprocal space is represented by Fourier-transforming  $D_p^{(l)}(\mathbf{r}_e)$  as

$$\mathcal{D}_{p}^{(l)}(\Delta \mathbf{K}_{p}) = (1/2\pi) \int_{\text{Min}(e_{p}^{(\pi)})}^{\text{Max}(e_{p}^{(\pi)})} \int_{p}^{\text{Max}(e_{p}^{(\sigma)})} D_{p}^{(l)}(\mathbf{r}_{e}) \\ \times \exp\left[-i2\pi(\eta_{p}^{(\sigma)}e_{p}^{(\sigma)} + \eta_{p}^{(\pi)}e_{p}^{(\pi)})\right] de_{p}^{(\sigma)} de_{p}^{(\pi)}.$$
(3)

Whereas the integration range of a Fourier transform is infinite in general, integration over a finite range is sufficient because  $D_p^{(l)}(\mathbf{r}_e)$  has a nonzero value only inside the bottom of the Borrmann pyramid in the present case.

Incidentally, X-ray amplitudes in three-beam pinhole topographs computer-simulated with the same procedure as described in Okitsu *et al.* (2006) are obtained for a location on the exit surface of the crystal:  $\mathbf{r}_e = i\mathbf{a} + j\mathbf{b}$ , where *i* and *j* are integers. Here, **a** and **b** are defined by

$$\mathbf{a} = (\mathbf{s}_g - \mathbf{s}_o) \frac{t}{n \cos \theta_{\rm B}},\tag{4}$$

$$\mathbf{b} = (\mathbf{s}_h - \mathbf{s}_o) \frac{t}{n \cos \theta_{\rm B}},\tag{5}$$

where *n* is the number of layers, each of which has thickness t/n. The three-beam T–T equation has been solved layer by layer, with layer thickness t/n, to obtain X-ray amplitudes on the exit surface.  $\theta_{\rm B}$  is the angle spanned by vectors **n** and  $\mathbf{s}_p$ , where **n** is the downward surface normal vector of the crystal defined by  $\mathbf{n} = \mathbf{a} \times \mathbf{b}/|\mathbf{a} \times \mathbf{b}|$ . For practical computer simulation of a pinhole topograph,  $D_p^{\prime(l)}(i, j)$  is defined such that  $D_p^{\prime(l)}(i, j) = D_p^{(l)}(i\mathbf{a} + j\mathbf{b}) [= D_p^{(l)}(\mathbf{r}_e)]$ . Further,  $D_p^{\prime(l)}(i, j)$  should be projected onto  $S_p$ . Let us define  $\mathbf{a}_p$  and  $\mathbf{b}_p$  by projecting  $\mathbf{a}$  and  $\mathbf{b}$  onto  $S_p$  as follows:

$$\mathbf{a}_{p} = \mathbf{a} + A_{p} \mathbf{s}_{p}$$
$$= A_{p}^{(\sigma)} \mathbf{e}_{p}^{(\sigma)} + A_{p}^{(\pi)} \mathbf{e}_{p}^{(\pi)}, \qquad (6)$$

$$\mathbf{b}_{p} = \mathbf{b} + B_{p} \mathbf{s}_{p}$$
  
=  $B_{p}^{(\sigma)} \mathbf{e}_{p}^{(\sigma)} + B_{p}^{(\pi)} \mathbf{e}_{p}^{(\pi)}.$  (7)

Here  $A_p$ ,  $B_p$ ,  $A_p^{(l)}$  and  $B_p^{(l)}$  ( $l \in \{\sigma, \pi\}$ ) are coefficients with dimension m and can be obtained by solving equations (6) and (7). Then  $D_p^{\prime(l)}(i, j)$  is projected to position  $\mathbf{r}_p = i\mathbf{a}_p + j\mathbf{b}_p$  on  $S_p$ . Next, reciprocal vectors  $\mathbf{a}_p^*$  and  $\mathbf{b}_p^*$  on  $S_p$  are defined as

a

$$\mathbf{a}_{p}^{*} = -\frac{\mathbf{s}_{p} \times \mathbf{b}_{p}}{\mathbf{s}_{p} \cdot (\mathbf{a}_{p} \times \mathbf{b}_{p})M}$$
$$= A_{p}^{*(\sigma)} \mathbf{e}_{p}^{(\sigma)} + A_{p}^{*(\pi)} \mathbf{e}_{p}^{(\pi)}, \qquad (8)$$

$$\mathbf{b}_{p}^{*} = \frac{\mathbf{s}_{p} \times \mathbf{a}_{p}}{\mathbf{s}_{p} \cdot (\mathbf{a}_{p} \times \mathbf{b}_{p})N}$$
$$= B_{p}^{*(\sigma)}\mathbf{e}_{p}^{(\sigma)} + B_{p}^{*(\pi)}\mathbf{e}_{p}^{(\pi)}, \tag{9}$$

such that  $\mathbf{a}_p \cdot \mathbf{a}_p^* = 1/M$ ,  $\mathbf{b}_p \cdot \mathbf{b}_p^* = 1/N$  and  $\mathbf{a}_p \cdot \mathbf{b}_p^* = \mathbf{b}_p \cdot \mathbf{a}_p^* = 0$ , where *M* and *N* are numbers in summations that will appear in (10). Here,  $A_p^{*(l)}$  and  $B_p^{*(l)}$  are coefficients with dimension of m<sup>-1</sup> which can be obtained by solving equations (8) and (9). Because equation (3) is satisfied even if  $\mathbf{r}_e$  is replaced by  $\mathbf{r}_p$ ,  $\mathcal{D}_p^{(l)}(k_i, k_j)$  at position  $k_i \mathbf{a}_p^* + k_j \mathbf{b}_p^*$  in the two-dimensional reciprocal space on  $S_p$  can be obtained by

$$\mathcal{D}_{p}^{\prime(l)}(k_{i},k_{j}) = \frac{\mathbf{s}_{p} \cdot (\mathbf{a}_{p} \times \mathbf{b}_{p})}{2\pi} \sum_{i=\mathrm{Min}(i)}^{\mathrm{Max}(i)} \sum_{j=\mathrm{Min}(j)}^{\mathrm{Max}(j)} D_{p}^{\prime(l)}(i,j)$$
$$\times \exp\left[-i2\pi(ik_{i}/M + jk_{j}/N)\right], \tag{10}$$

where M = Max(i) - Min(i) + 1, N = Max(j) - Min(j) + 1.

To obtain the rocking curves as a function of  $\Delta \omega$  and  $\Delta \psi$ , which are rotation angles of the crystal around the  $\mathbf{e}_o^{(\sigma)}$  and  $\mathbf{e}_o^{(\pi)}$ axes, projections of  $\omega_{\text{step}} K \mathbf{e}_o^{(\pi)}$  and  $\psi_{\text{step}} K \mathbf{e}_o^{(\sigma)}$  on  $S_p$  should be considered. Here  $\omega_{\text{step}}$  and  $\psi_{\text{step}}$  are angular steps when rotating the crystal around the  $\mathbf{e}_o^{(\sigma)}$  and  $\mathbf{e}_o^{(\pi)}$  axes, respectively. These vectors  $\mathbf{a}_p^{*'}$  and  $\mathbf{b}_p^{*'}$  projected on  $S_p$  can be calculated by

$$\mathbf{a}_{p}^{*\prime} = \omega_{\text{step}} \mathbf{K} \mathbf{e}_{o}^{(\sigma)} + A_{p}^{*\prime} \mathbf{n}$$
$$= A_{p}^{*\prime(\sigma)} \mathbf{e}_{p}^{(\sigma)} + A_{p}^{*\prime(\pi)} \mathbf{e}_{p}^{(\pi)}, \qquad (11)$$

$$\mathbf{b}_{p}^{*\prime} = \psi_{\text{step}} K \mathbf{e}_{o}^{(\pi)} + B_{p}^{*\prime} \mathbf{n}$$
$$= B_{p}^{*\prime(\sigma)} \mathbf{e}_{p}^{(\sigma)} + B_{p}^{*\prime(\pi)} \mathbf{e}_{p}^{(\pi)}.$$
(12)

Here  $A_p^{**}$ ,  $B_p^{**}$ ,  $A_p^{**(l)}$  and  $B_p^{**(l)}$  are coefficients with dimension  $\mathbf{m}^{-1}$  which can be obtained by solving equations (11) and (12).  $\mathcal{D}_p^{\prime(l)}(k_i, k_j)$  can be transformed to  $\mathcal{D}_p^{\prime(l)}(\Delta \omega, \Delta \psi)$  as a function of  $\Delta \omega$  (=  $k_i' \omega_{\text{step}}$ ) and  $\Delta \psi$  (=  $k_j' \psi_{\text{step}}$ ), where  $k_i'$  and  $k_j'$  are no longer integers. Because  $k_i \mathbf{a}_p^* + k_j \mathbf{b}_p^* = k_i' \mathbf{a}_p^{**} + k_j' \mathbf{b}_p^{**}$ , the relation between  $k_i$ ,  $k_j$  and  $k_i'$ ,  $k_j'$  is represented as

$$\mathbf{M}\mathbf{X} = \mathbf{M}'\mathbf{X}',$$

where

$$\mathbf{M} = \begin{pmatrix} A_p^{*(\sigma)} & B_p^{*(\sigma)} \\ A_p^{*(\pi)} & B_p^{*(\pi)} \end{pmatrix}, \quad \mathbf{X} = \begin{pmatrix} k_i \\ k_j \end{pmatrix}$$

#### Table 1

Parameters of X-ray reflection indices of a silicon crystal.

The parameters were calculated for a photon energy of 12.0 keV using XINPRO of XOP 2.11;  $\theta_{\rm B}$  is the Bragg reflection angle and  $|\chi_{\rm hr}|$  and  $|\chi_{\rm hi}|$  are the absolute values of the real and imaginary parts of  $\chi_{\rm h}$ . Here  $\chi_{\rm h}$  is the *h*th-order Fourier coefficient of electric susceptibility.  $\Lambda_L^{(\sigma)}$  and  $\Lambda_L^{(\pi)}$  are the *Pendellösung* distances for transmission geometry defined in Authier (2004) for  $\sigma$ - and  $\pi$ -polarized X-rays in the two-beam case.

h	$\theta_{\rm B}$ (°)	$ \chi_{hr}   imes 10^6$	$ \chi_{\rm hi}   imes 10^8$	$\Lambda_L^{(\sigma)}$ (µm)	$\Lambda_L^{(\pi)}$ (µm)
000	0	6.77391	7.19974	15.25	15.25
044	32.5539	2.63570	6.33738	33.03	78.48
440	32.5539	2.63570	6.33738	33.03	78.48

$$\mathbf{M}' = \begin{pmatrix} A_p^{*(\sigma)} & B_p^{*(\sigma)} \\ A_p^{*(\pi)} & B_p^{*(\pi)} \end{pmatrix}, \quad \mathbf{X}' = \begin{pmatrix} k'_i \\ k'_j \end{pmatrix}.$$

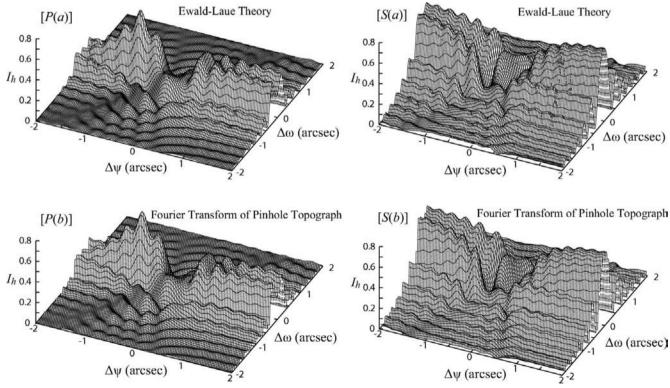
Therefore,  $k'_i$  and  $k'_j$  can be obtained by  $\mathbf{X}' = \mathbf{M}'^{-1}\mathbf{M}\mathbf{X}$ .

Three-beam rocking curves can also be calculated by solving the eigenvalue/eigenvector problem of the three-beam E–L theory as described in Colella (1974). Values of  $\omega_{\text{step}}$  and  $\psi_{\text{step}}$  in equations (11) and (12) should be sufficiently small to obtain two-dimensional rocking curves that are precise enough. Simultaneously, the value of t/n should be sufficiently small compared with the *Pendellösung* distance  $\Lambda_L^{(l)}$  (see Table 1) to calculate the X-ray amplitudes in the pinhole topographs.

In the cases of both Figs. 1 and 2, *M* and *N* in equations (8) and (9) were set to be  $M = N = 8192 \ (= 2^{13})$  to satisfy the above two requirements simultaneously and to use the fast-Fourier-transform algorithm (Cooley & Tukey, 1965). Min(*k*) and Max(*k*) ( $k \in \{i, j\}$ ) were adjusted such that the triangular region corresponding to the bottom of the Borrmann pyramid was placed in the central part of the summation range in equation (10).

#### 3. Results and discussion

Figs. 1 and 2 show X-ray rocking curves of the *h* wave that were calculated based on the E–L theory, [X(a)] ( $X \in \{P, S\}$ ), and by fast-Fourier-transforming the X-ray amplitudes in computer-simulated pinhole topographs, [X(b)]. A symmetrical transmission geometry of the three-beam case with h =044, g = 440 and incident X-rays  $\pi$ -polarized for [P(x)]( $x \in \{a, b\}$ ) and  $\sigma$ -polarized for [S(x)] were assumed for both Figs. 1 and 2. The three-beam T–T equation was solved in the same way as described in Okitsu *et al.* (2006) to obtain the X-ray amplitudes in pinhole topographs. The values of *t* and *n* in equations (4) and (5) were  $t = 75 \ \mu m$  and n = 1023 for Fig. 1, and  $t = 7.5 \ \mu m$  and n = 1023 for Fig. 2. The reflection parameters calculated by using XINPRO of XOP 2.11 (Sanchez del Rio & Dejus, 1998) are summarized in Table 1 and were



#### Figure 1

X-ray three-beam rocking curves of the *h* wave at a photon energy of 12 keV (wavelength 1.033 Å) for a symmetrical transmission geometry obtained by [X(a)] ( $X \in \{P, S\}$ ) solving the eigenvalue/eigenvector problem of the three-beam Ewald–Laue dynamical theory and [X(b)] fast-Fourier-transforming X-ray amplitudes on the exit surface of the crystal of three-beam pinhole topographs which have been computer-simulated based on the Takagi–Taupin equation. X-rays  $\pi$ -polarized for P(x) ( $x \in \{a, b\}$ ) and  $\sigma$ -polarized for S(x) incident on a silicon crystal with a thickness  $t = 75 \ \mu m$  were assumed. Angular variables  $\Delta \omega$  and  $\Delta \psi$  are presented in arcsec.  $I_h$  is the reflectivity defined by  $I_h = |\mathcal{D}_h^{\prime(\sigma)}(\Delta \omega, \Delta \psi)|^2 + |\mathcal{D}_h^{\prime(\pi)}(\Delta \omega, \Delta \psi)|^2$ , where  $\Delta \omega = k'_i \omega_{step}$  and  $\Delta \psi = k'_i \psi_{step}$ .

used for the calculations. Signs of the angular deviations  $\Delta \omega$ and  $\Delta \psi$  were taken to be positive when the reflection angles of the *h* or *g* reflections were higher than the exact threebeam condition. In both Figs. 1 and 2, the reflectivity  $I_h$  was defined by  $I_h = |\mathcal{D}_h^{\prime(\sigma)}(\Delta \omega, \Delta \psi)|^2 + |\mathcal{D}_h^{\prime\prime(\pi)}(\Delta \omega, \Delta \psi)|^2$ , where  $\Delta \omega = k'_i \omega_{\text{step}}$  and  $\Delta \psi = k'_j \psi_{\text{step}}$ . Good agreements were found between [X(a)] and [X(b)] ( $X \in \{P, S\}$ ) in both Figs. 1 and 2.

It has been pointed out by Weckert & Hümmer (1998) that *t* should be sufficiently small compared with the *Pendellösung* distance  $\Lambda_L^{(l)}$  ( $l \in \{\sigma, \pi\}$ ) if phase information is to be extracted from the three-beam rocking curves. While the case of Fig. 1 does not satisfy this requirement, the case of Fig. 2 does.

It has been shown that three-beam rocking curves for a perfect crystal, which are usually calculated based on the E–L theory, can also be computed by Fourier-transforming the amplitudes in computer-simulated pinhole topographs based on the T–T equation, at least for a symmetrical transmission geometry. The method using the T–T equation is able to deal with an arbitrary-shaped crystal, whereas the E–L theory can only deal with a semi-infinite perfect crystal with planar surfaces. The three-beam T–T equation can deal with cases in which transmission and reflection geometries coexist. Furthermore, this method for obtaining X-ray rocking curves is expected to be applicable to any *n*-beam ( $n \in \{3, 4, 5, 6, 8, 12\}$ ) cases.

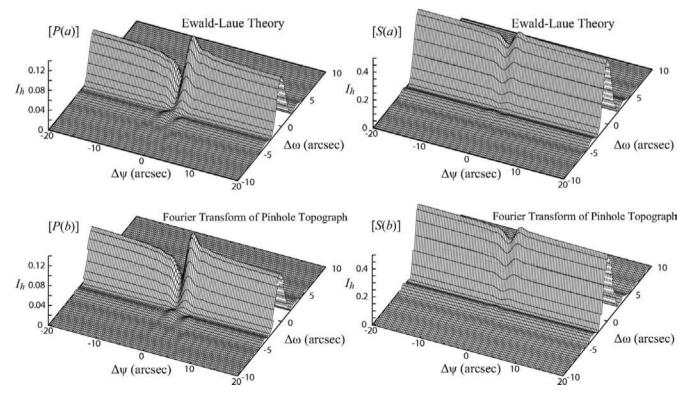
#### 4. Conclusion

It has been shown that three-beam X-ray rocking curves can also be calculated by fast-Fourier-transforming X-ray amplitudes in computer-simulated pinhole topographs based on the three-beam T–T equation. With this method it is possible to deal with an arbitrary-shaped crystal when phase information on crystal structure factors is to be extracted by using the three-beam method.

The super computers HP-XC4000 (ismxc), HITACHI-SR11000 (ismsr), NEC-SX6 (ismsx), SGI-ALTIX3700 (ismaltix), SGI-PRISM (ismprsm), Fujitsu-PRIMERGY (ismrx) and Fujitsu-SPARC-Enterprise (isment) of the Institute of Statistical Mathematics and HITACHI-SR11000 (sumire) of the Institute for Solid State Physics of the University of Tokyo were used in the present work.

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#### Figure 2

Three-beam rocking curves of the *h* beam. The crystal thickness  $t = 7.5 \,\mu\text{m}$ , in which the condition that *t* is sufficiently smaller than the *Pendellösung* distance  $\Lambda_{L}^{(l)}$  ( $l \in \{\sigma, \pi\}$ , see Table 1) is satisfied (Weckert & Hümmer, 1998). The other assumed conditions are identical with those for Fig. 1. [*P*(*x*)] and [*S*(*x*)] ( $x \in \{a, b\}$ ) correspond to [*P*(*x*)] and [*S*(*x*)] of Fig. 1.

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